



HiPer SMALL SPOT MAPPING

HiPer Small Spot Mapping is the latest addition to the Zetium platform and its SumXcore technology – an integration of WDXRF, EDXRF and XRD.

With the unique X-ray optics of HiPer Small Spot Mapping, measurement times can be reduced by up to 80%. This puts the Zetium in a class of its own with respect to analytical power, speed and task flexibility in a wide range of environments.

- Small spot mapping available on your spectrometer for production control
- Inclusion analysis in just minutes or map over 100 mm² in only a few hours
- · Cover Na to Am and screen for unexpected elements
- Schedule and run small spot mapping on sample batches

www.malvernpanalytical.com/HiPer



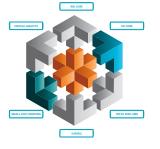


ZETIUM - ELEMENTAL EXCELLENCE

Elemental innovation

Continuous development, improved customer experience

The Zetium platform embodies SumXcore technology - an integration of WDXRF, EDXRF and XRD, creating a revolutionary step in materials analysis.



Elemental intelligence

SuperQ, evolutionary software for a revolutionary platform

With the integrated intelligence of the Virtual Analyst, SuperQ software provides guidance on the optimal setup for each experiment.



Elemental technology

60 years of experience and heritage - the ideal starting point

Zetium is designed to set new standards in terms of analytical power, usability and sustainability, to users in process optimization, quality control and research.

- Flexible sample handling
- Intelligent sample introduction
- Unrivalled accuracy & reproducibility



Elemental support

Transparent and reliable

- Service
- Expertise
- · Training & education
- Analysis & standards preparation



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